

## IGBT - Power, Co-PAK N-Channel, Field Stop VII (FS7), SCR, Power TO247-3L, 1200 V, 1.4 V, 100 A

## FGY100T120RWD

#### Description

Using the novel field stop 7<sup>th</sup> generation IGBT technology and the Gen7 Diode in TP247 3-lead package, FGY100T120RWD offers the optimum performance with low conduction losses and good switching controllability for a high efficiency operation in various applications like motor control, UPS, data center and high-power switch.

#### **Features**

- Low Conduction Loss and Optimized Switching
- Maximum Junction Temperature  $T_I = 175$ °C
- Positive Temperature Coefficient for Easy Parallel Operation
- High Current Capability
- 100% of the Parts are Dynamically Tested
- Short Circuit Rated
- RoHS Compliant

#### **Applications**

- Motor Control
- UPS
- General Application Requiring High Power Switch

#### MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise noted)

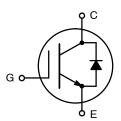
Parameter		Symbol	Value	Unit
Collector to Emitter Voltage		V <sub>CES</sub>	1200	V
Gate to Emitter Voltage		$V_{GES}$	±20	
Transient Gate to Emitter	Voltage		±30	
Collector Current	T <sub>C</sub> = 25°C	Ic	200	Α
	T <sub>C</sub> = 100°C		100	
Power Dissipation	T <sub>C</sub> = 25°C	$P_{D}$	1495	W
	T <sub>C</sub> = 100°C		747	
Pulsed Collector Current	$T_{C} = 25^{\circ}C,$ $t_{p} = 10 \ \mu s$ (Note 1)	I <sub>CM</sub>	300	Α
Diode Forward	T <sub>C</sub> = 25°C	IF	200	
Current	T <sub>C</sub> = 100°C		100	
Pulsed Diode Forward Current	$T_{C} = 25^{\circ}C,$ $t_{p} = 10 \mu s$ (Note 1)	I <sub>FM</sub>	300	
Short Circuit Withstand Time V <sub>GE</sub> = 15 V, V <sub>CC</sub> = 600 V, T <sub>C</sub> = 150°C		T <sub>SC</sub>	5	μs
Operating Junction and Storage Temperature		T <sub>J</sub> , T <sub>STG</sub>	-55 to 175	°C
Lead Temperature for Soldering Purposes		$T_L$	260	

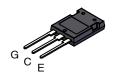
Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Repetitive rating: pulse width limited by max. Junction temperature.

BV <sub>CES</sub>	V <sub>CE(SAT)</sub>	Ic
1200 V	1.4 V	100 A

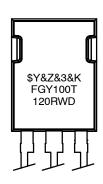
#### **PIN CONNECTIONS**





TO247-3LD CASE 340CD

#### **MARKING DIAGRAM**



\$Y	= <b>onsemi</b> logo
&Z	= Assembly Plant Code
&3	= 3-Digit Date Code
&K	= 2-Digit Lot Traceability Code
FGY100T120RWD	= Specific Device Code

#### **ORDERING INFORMATION**

Device	Package	Shipping
FGY100T120RWD	TO247-3LD (Pb-Free)	30 Units / Tube

#### THERMAL CHARACTERISTICS

Parameter	Symbol	Max Value	Unit
Thermal Resistance, Junction to Case for IGBT	$R_{ heta JC}$	0.1	°C/W
Thermal Resistance, Junction to Case for Diode		0.19	
Thermal Resistance, Junction to Ambient	$R_{ heta JA}$	40	

# ELECTRICAL CHARACTERISTICS OF THE IGBT (T<sub>J</sub> = 25°C unless otherwise noted) Parameter Symbol Test Conditions

Parameter	Symbol	Test Conditions	Min	Тур	Max	Unit
OFF CHARACTERISTICS						
Collector to Emitter Breakdown Voltage	BV <sub>CES</sub>	$V_{GE} = 0 \text{ V, } I_{C} = 5 \text{ mA}$	1200	-	-	V
Breakdown Voltage Temperature Coefficient	$\Delta BV_{CES}  /  \Delta T_{J}$	$V_{GE} = 0 \text{ V, } I_C = 5 \text{ mA}$	-	662	-	mV/°C
Collector to Emitter Cut-Off Current	I <sub>CES</sub>	V <sub>GE</sub> = 0 V, V <sub>CE</sub> = V <sub>CES</sub>	_	_	40	μΑ
Gate to Emitter Leakage Current	I <sub>GES</sub>	V <sub>GE</sub> = 20 V, V <sub>CE</sub> = 0 V	-	-	±400	nA
ON CHARACTERISTICS						
Gate to Emitter Threshold Voltage	V <sub>GE(TH)</sub>	$V_{GE} = V_{CE}$ , $I_C = 100 \text{ mA}$	4.9	5.92	6.7	V
Collector to Emitter Saturation	V <sub>CE(SAT)</sub>	V <sub>GE</sub> = 15 V, I <sub>C</sub> = 100 A, T <sub>J</sub> = 25°C	1.15	1.43	1.75	V
Voltage		V <sub>GE</sub> = 15 V, I <sub>C</sub> = 100 A, T <sub>J</sub> = 175°C	-	1.66	-	1
DYNAMIC CHARACTERISTICS						
Input Capacitance	C <sub>IES</sub>	V <sub>CE</sub> = 30 V, V <sub>GE</sub> = 0 V, f = 1 MHz	-	12200	_	pF
Output Capacitance	C <sub>OES</sub>		-	392	-	
Reverse Transfer Capacitance	C <sub>RES</sub>		-	44.2	-	1
Total Gate Charge	$Q_{G}$	V <sub>CE</sub> = 600 V, V <sub>GE</sub> = 15 V,	-	427	-	nC
Gate to Emitter Charge	$Q_GE$	I <sub>C</sub> = 100 A	-	108	-	]
Gate to Collector Charge	Q <sub>GC</sub>	]	-	161	-	
SWITCHING CHARACTERISTIC, II	NDUCTIVE LOAI	D				
Turn-On Delay Time	t <sub>d(on)</sub>	V <sub>CE</sub> = 600 V, V <sub>GE</sub> = 15 V,	-	74	-	ns
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_C$ = 50 A, $R_G$ = 4.7 Ω, $T_J$ = 25°C	-	464	-	ns
Rise Time	t <sub>r</sub>	]	-	45	-	ns
Fall Time	t <sub>f</sub>		-	196	-	1
Turn-On Switching Loss	E <sub>on</sub>		-	3.43	-	mJ
Turn-Off Switching Loss	E <sub>off</sub>		-	4.54	-	1
Total Switching Loss	E <sub>ts</sub>		-	7.97	-	1
Turn-On Delay Time	t <sub>d(on)</sub>	V <sub>CE</sub> = 600 V, V <sub>GE</sub> = 15 V,	-	80	-	ns
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_C$ = 100 A, $R_G$ = 4.7 Ω, $T_J$ = 25°C	-	364	-	ns
Rise Time	t <sub>r</sub>		-	85	-	ns
Fall Time	t <sub>f</sub>		-	180	-	1
Turn-On Switching Loss	E <sub>on</sub>	1	-	8.13	-	mJ
Turn-Off Switching Loss	E <sub>off</sub>	1	-	7.05	-	1
Total Switching Loss	E <sub>ts</sub>	1	-	15.18	-	1

**ELECTRICAL CHARACTERISTICS OF THE IGBT** (T<sub>J</sub> = 25°C unless otherwise noted) (continued)

Parameter	Symbol	Test Conditions	Min	Тур	Max	Unit
SWITCHING CHARACTERISTIC, IN	NDUCTIVE LO	/D	•	•		•
Turn-On Delay Time	t <sub>d(on)</sub>	$V_{CE} = 600 \text{ V}, V_{GE} = 15 \text{ V},$	-	70	_	ns
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_C = 50 \text{ A}, R_G = 4.7 \Omega,$ $T_{,1} = 175 ^{\circ}\text{C}$	_	536	-	ns
Rise Time	t <sub>r</sub>	7	-	50	-	ns
Fall Time	t <sub>f</sub>		-	348	-	1
Turn-On Switching Loss	E <sub>on</sub>		-	5.58	-	mJ
Turn-Off Switching Loss	E <sub>off</sub>		-	6.83	-	1
Total Switching Loss	E <sub>ts</sub>	1	_	12.41	-	1
Turn-On Delay Time	t <sub>d(on)</sub>	V <sub>CE</sub> = 600 V, V <sub>GE</sub> = 15 V,	-	78	-	ns
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_C$ = 100 A, R <sub>G</sub> = 4.7 Ω, T <sub>J</sub> = 175°C	_	412	-	ns
Rise Time	t <sub>r</sub>		_	93	-	ns
Fall Time	t <sub>f</sub>		_	316	-	
Turn-On Switching Loss	E <sub>on</sub>		_	12.00	-	mJ
Turn-Off Switching Loss	E <sub>off</sub>		=	10.30	-	
Total Switching Loss	E <sub>ts</sub>		=	22.30	-	
DIODE CHARACTERISTIC						
Diode Forward Voltage	V <sub>F</sub>	I <sub>F</sub> = 100 A, T <sub>J</sub> = 25°C	1.46	1.80	2.08	V
		I <sub>F</sub> = 100 A, T <sub>J</sub> = 175°C	-	1.90	-	
DIODE SWITCHING CHARACTERI	STIC, INDUCT	IVE LOAD				
Reverse Recovery Time	t <sub>rr</sub>	$V_R = 600 \text{ V}, I_F = 50 \text{ A},$	_	256	_	ns
Reverse Recovery Charge	Q <sub>rr</sub>	$dI_F/dt = 500 \text{ A/}\mu\text{s},$ $T_J = 25^{\circ}\text{C}$	_	3140	-	nC
Reverse Recovery Energy	E <sub>rec</sub>	1	-	1	-	mJ
Peak Reverse Recovery Current	I <sub>RRM</sub>		_	24.5	-	Α
Reverse Recovery Time	t <sub>rr</sub>	$V_R = 600 \text{ V}, I_F = 100 \text{ A},$	-	347	-	ns
Reverse Recovery Charge	Q <sub>rr</sub>	$H_{J} = 500 \text{ A/}\mu\text{s},$ $H_{J} = 25^{\circ}\text{C}$	_	4408	-	nC
Reverse Recovery Energy	E <sub>rec</sub>		=	2	-	mJ
Peak Reverse Recovery Current	I <sub>RRM</sub>		_	25.8	-	Α
Reverse Recovery Time	t <sub>rr</sub>	$V_R = 600 \text{ V}, I_F = 50 \text{ A},$	-	424	-	ns
Reverse Recovery Charge	Q <sub>rr</sub>	dl <sub>F</sub> /dt = 500 A/μs, T <sub>J</sub> = 175°C	_	8610	-	nC
Reverse Recovery Energy	E <sub>rec</sub>	1	_	4	-	mJ
Peak Reverse Recovery Current	I <sub>RRM</sub>		_	40.8	-	Α
Reverse Recovery Time	t <sub>rr</sub>	V <sub>R</sub> = 600 V, I <sub>F</sub> = 100 A,	-	572	-	ns
Reverse Recovery Charge	Q <sub>rr</sub>	dl <sub>F</sub> /dt = 500 A/μs, T <sub>J</sub> = 175°C	-	12476	-	nC
Reverse Recovery Energy	E <sub>rec</sub>	7	_	5	_	mJ
Peak Reverse Recovery Current	I <sub>RRM</sub>		_	43.6	_	Α

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

#### **TYPICAL CHARACTERISTICS**

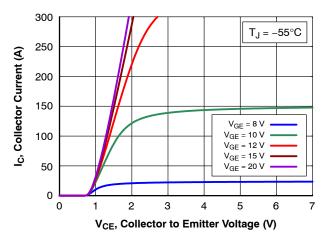


Figure 1. Output Characteristics

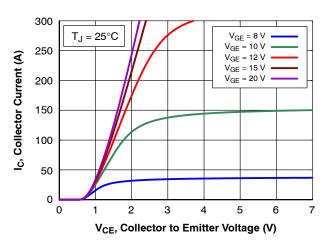


Figure 2. Output Characteristics

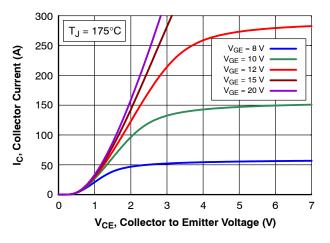


Figure 3. Output Characteristics

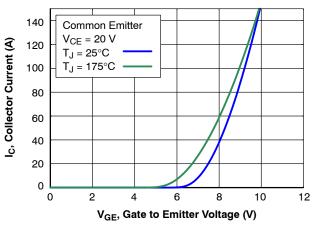


Figure 4. Transfer Characteristics

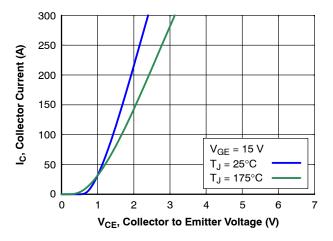


Figure 5. Saturation Voltage Characteristics

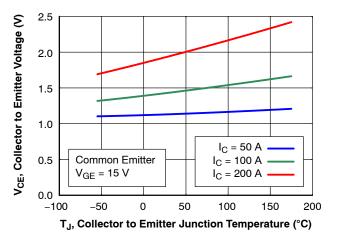


Figure 6. Saturation Voltage vs Junction Temperature

#### TYPICAL CHARACTERISTICS (CONTINUED)

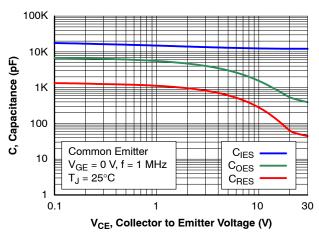


Figure 7. Capacitance Characteristics

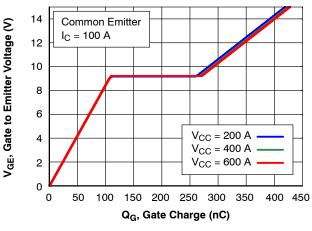


Figure 8. Gate Charge Characteristics

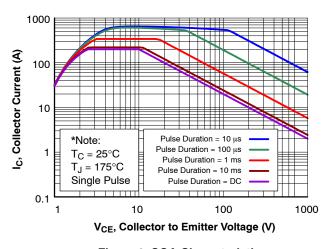


Figure 9. SOA Characteristics

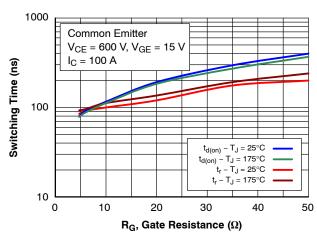


Figure 10. Turn-On Time vs Gate Resistance

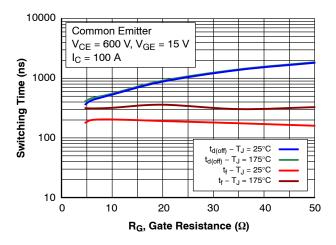


Figure 11. Turn-Off Time vs Gate Resistance

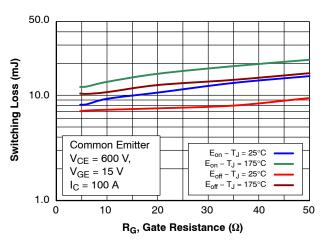


Figure 12. Switching Loss vs Gate Resistance

#### TYPICAL CHARACTERISTICS (CONTINUED)

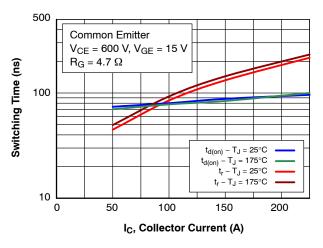


Figure 13. Turn-On Time vs Collector Current

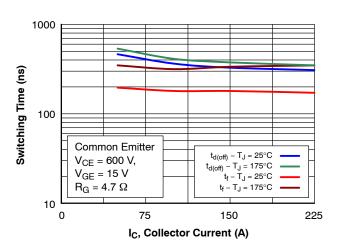


Figure 14. Turn-Off Time vs Collector Current

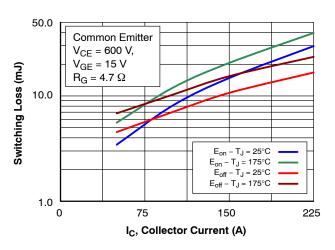


Figure 15. Switching Loss vs Collector Current

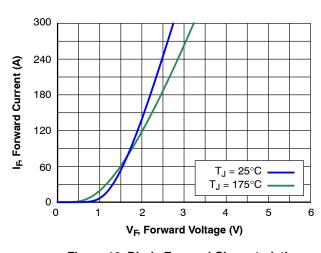


Figure 16. Diode Forward Characteristics

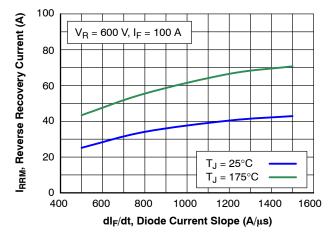


Figure 17. Diode Reverse Recovery Current

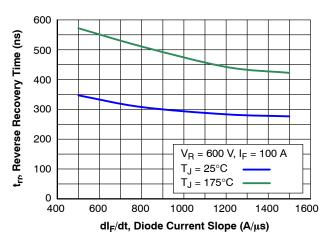


Figure 18. Diode Reverse Recovery Time

#### TYPICAL CHARACTERISTICS (CONTINUED)

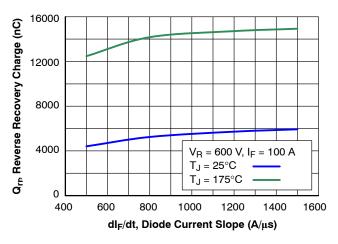


Figure 19. Diode Stored Charge Characteristics

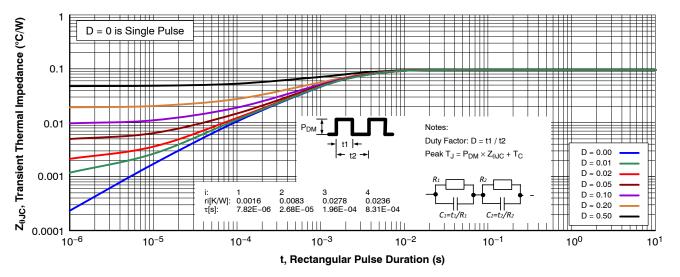


Figure 20. Transient Thermal Impedance of IGBT

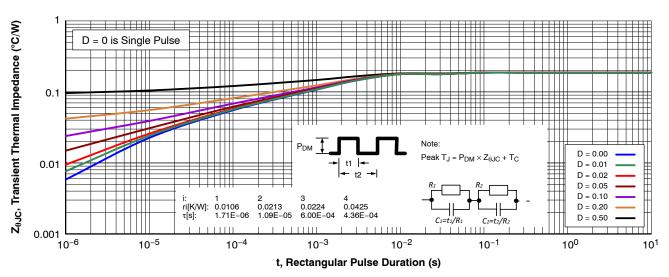


Figure 21. Transient Thermal Impedance of Diode

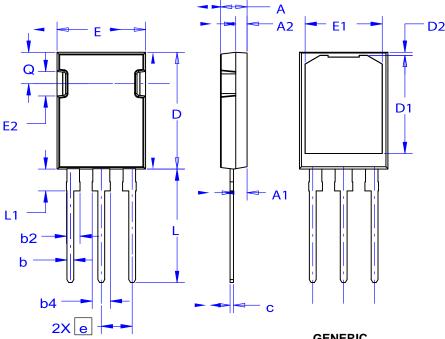


TO-247-3LD CASE 340CD ISSUE A

**DATE 18 SEP 2018** 

#### NOTES:

- A. THIS PACKAGE DOES NOT CONFORM TO ANY STANDARDS.
- B. ALL DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH AND TIE BAR PROTRUSIONS.
- D. DIMENSION AND TOLERANCE AS PER ASME Y14.5-2009.



DIM	MILLIMETERS					
DIM	MIN	NOM	MAX			
Α	4.58	4.70	4.82			
<b>A</b> 1	2.20	2.40	2.60			
A2	1.80	2.00	2.20			
D	20.32	20.57	20.82			
Е	15.37	15.62	15.87			
E2	4.12	4.32	4.52			
е	~	5.45	~			
L	19.90	20.00	20.10			
L1	3.69	3.81	3.93			
Q	5.34	5.46	5.58			
b	1.10	1.20	1.30			
b2	2.10	2.24	2.39			
b4	2.87	3.04	3.20			
С	0.51	0.61	0.71			
D1	16.63	16.83	17.03			
D2	0.51	0.93	1.35			
E1	13.40	13.60	13.80			

## GENERIC MARKING DIAGRAM\*

XXXXXXXX AYWWG

XXXX = Specific Device Code

A = Assembly Location

Y = Year WW = Work Week G = Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.

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